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PATENT APPLICATION

ATTORNEY DOCKET NO. 10011201-1

IN THE
UNITED STATES PATENT AND TRADEMARK OFFICE

Inventor(s): David C. Chu

Serial No.:

Examiner:

Filing Date: Herewith

Group Art Unit:

Title: SYSTEM AND METHOD FOR INTERFEROMETER NON-LINEARITY COMPENSATION



COMMISSIONER FOR PATENTS
Washington, D.C. 20231

INFORMATION DISCLOSURE STATEMENT

Sir:

This Information Disclosure Statement is submitted:

- ☒ under 37 CFR 1.97(b), or
(Within three months of filing national application; or date of entry of national application; or before mailing date of first office action on the merits; whichever occurs last)
- ☐ under 37 CFR 1.97(c) together with either a:
☐ Statement under 37 CFR 1.97(e), or
☐ a \$180.00 Processing fee under 37 CFR 1.17(p), or
(After the CFR 1.97 (b) time period, but before final action or notice of allowance, whichever occurs first)
- ☐ under 37 CFR 1.97 (d) together with a:
☐ Statement under 37 CFR 1.97(e), and
☐ a \$180.00 processing fee under 37 CFR 1.17(p).
(Filed after final action or notice of allowance, whichever occurs first, but before payment of the issue fee)

Please charge to Deposit Account 50-1078 the sum of \$0.00. At any time during the pendency of this application, please charge any fees required or credit any overpayment to Deposit Account 50-1078 pursuant to 37 CFR 1.25.

☐ Applicant(s) submit herewith Form PTO 1449. All the references identified herein were disclosed in Patent Application No. _____ filed _____, now U. S. Patent No. _____, and, as such, copies thereof are not included pursuant to the provisions of 37 CFR 1.98(d).

☐ A concise explanation of the relevance of foreign language patents, foreign language publications and other foreign language information listed on PTO Form 1449, as presently understood by the individuals(s) designated in 37 CFR 1.56 (c) most knowledgeable about the content is given on the attached sheet, or where a foreign language patent is cited in a search report or other action by a foreign patent office in a counterpart foreign application, an English language version of the search report or action which indicates the degree of relevance found by the foreign office is listed on form PTO 1449 and is enclosed herewith.

It is requested that the information disclosed herein be made of record in this application.

"Express Mail" label no. EL 074 326 298 US

Date of Deposit Nov. 13, 2001

I hereby certify that this is being deposited with the United States Postal Service "Express Mail Post Office to Addressee" service under 37 CFR 1.10 on the date indicated above and is addressed to: Commissioner for Patents, Washington, D.C. 20231.

By

Typed Name: Christina Plichta

Respectfully submitted,

David C. Chu

By

Jeff A. Holmen

Attorney/Agent for Applicant(s)

Reg. No. 38,492

Date: Nov. 13, 2001

FORM PTO-14

LIST OF PATENTS AND PUBLICATIONS FOR
APPLICANT'S INFORMATION DISCLOSURE
STATEMENT

(Use several sheets if necessary)

ATTY. DOCKET NO.

10011201-1

APPLICATION NO.

CONFIRMATION NO.

APPLICANT

David C. Chu

FILING DATE

Herewith

GROUP

 Jc618 U.S. PTO
 10/10/17
 11/13/01

REFERENCE DESIGNATION

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
	1A	5,166,959	Nov. 24, 1992	Chu et al.		
	1B	5,663,666	Sept. 2, 1992	Chu et al.		
	1C					
	1D					
	1E					
	1F					
	1G					
	1H					
	1I					
	1J					
	1K					

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	TRANSLATION	
							YES	NO
	1L							
	1M							
	1N							
	1O							
	1P							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

	1Q	"Single frequency laser interferometer with subnanometer accuracy"; T. Eom, T. Choi, Proc. of 2nd Euspen International Conference - Turin, Italy - May 27th to 31st, 2001.
	1R	"High-resolution, High-speed, Low Data Age Uncertainty, Heterodyne Displacement Measuring Interferometer Electronics"; Frank C. Demarest; Meas. Sci. Technol.; pp. 1024-1030; 1998.
	1S	"Spectrum" article; IEEE; pp. 28-32; 1988.

EXAMINER

DATE CONSIDERED